

Eee PC

(M/N: Eee PC 1015PN)

Test Photograph of CE&RE

Test Mode: Transmitting

Description: Front View of Conducted Emission Test Setup



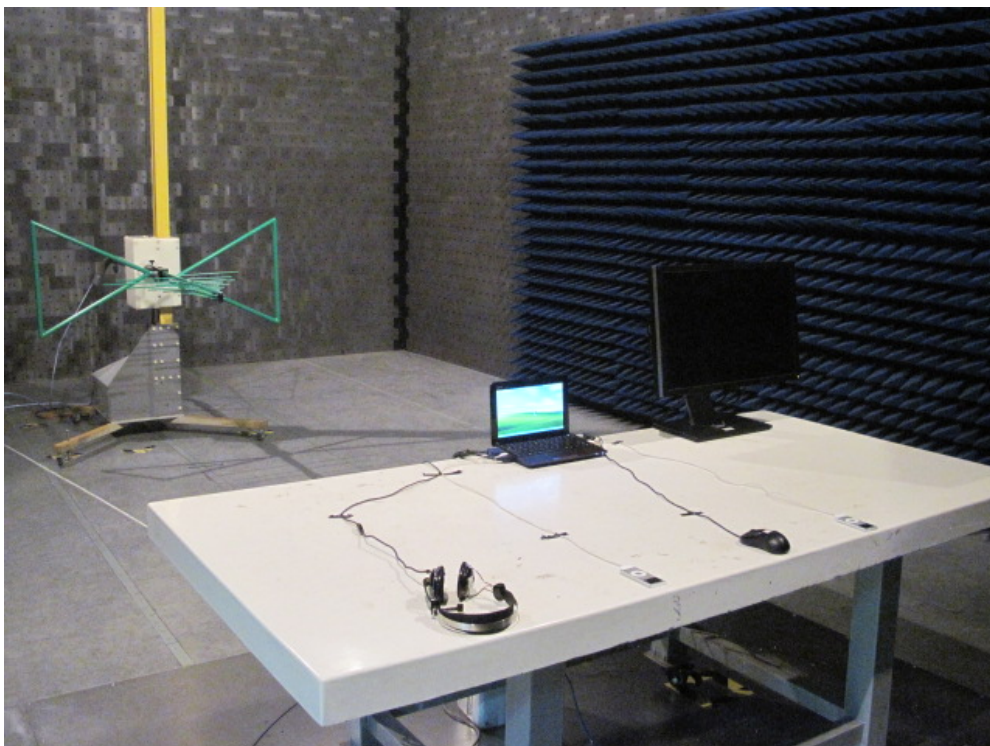
Test Mode: Transmitting

Description: Back View of Conducted Emission Test Setup



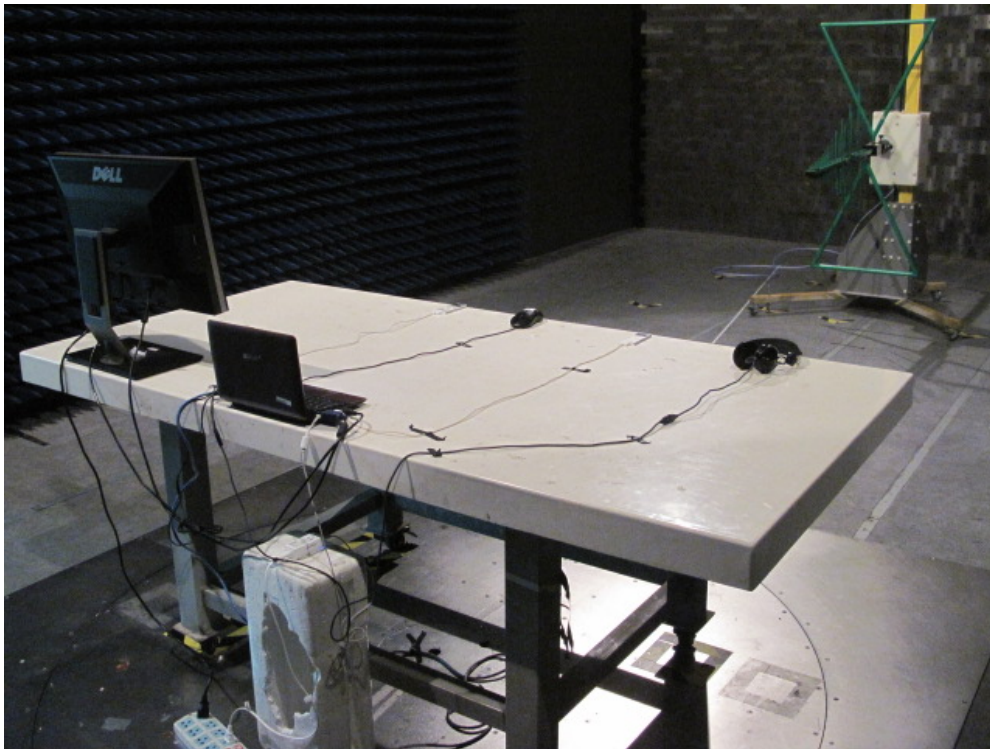
Test Mode : Transmitting

Description : Front View of Radiated Emission Test Setup for Below 1GHz



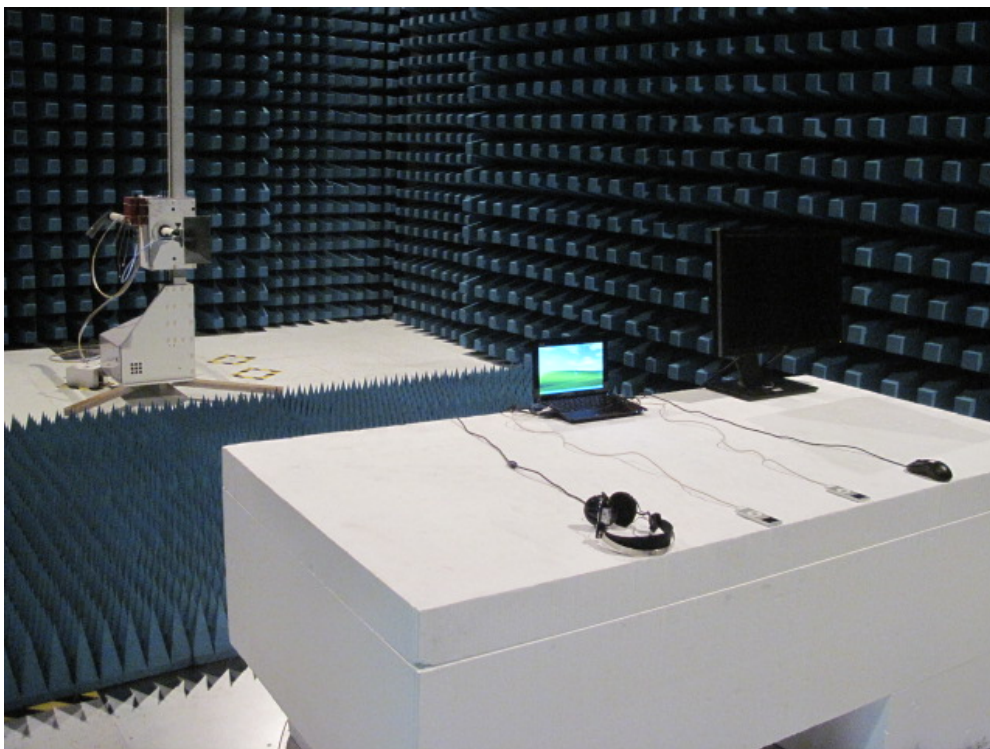
Test Mode : Transmitting

Description : Back View of Radiated Emission Test Setup for Below 1GHz



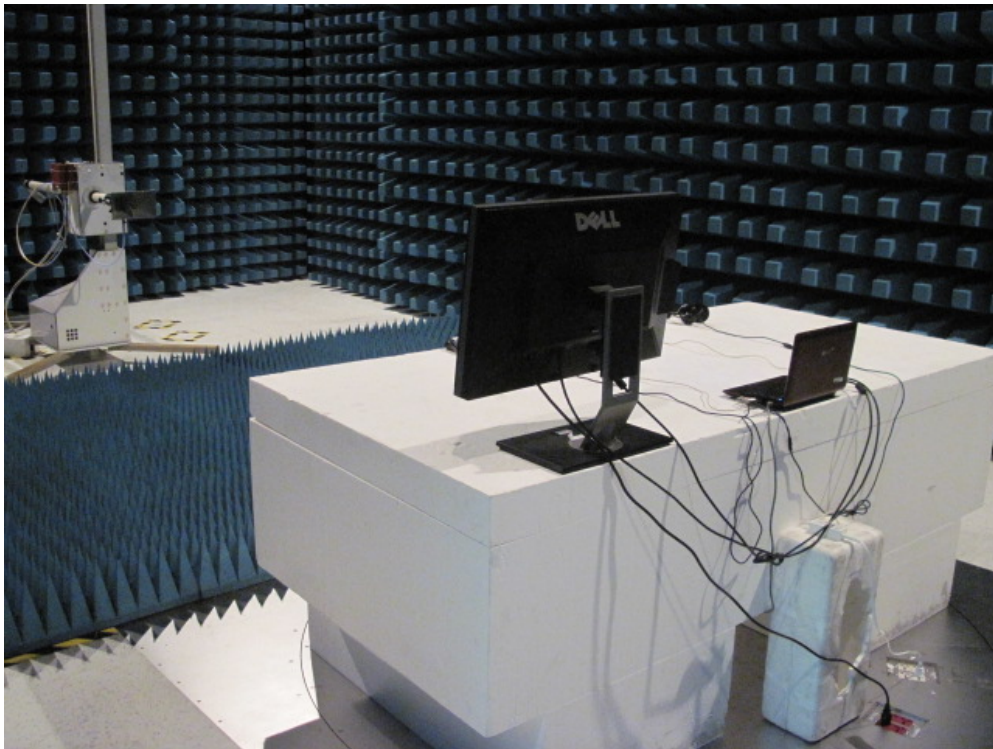
Test Mode : Transmitting

Description : Front View of Radiated Emission Test Setup for 1~18GHz



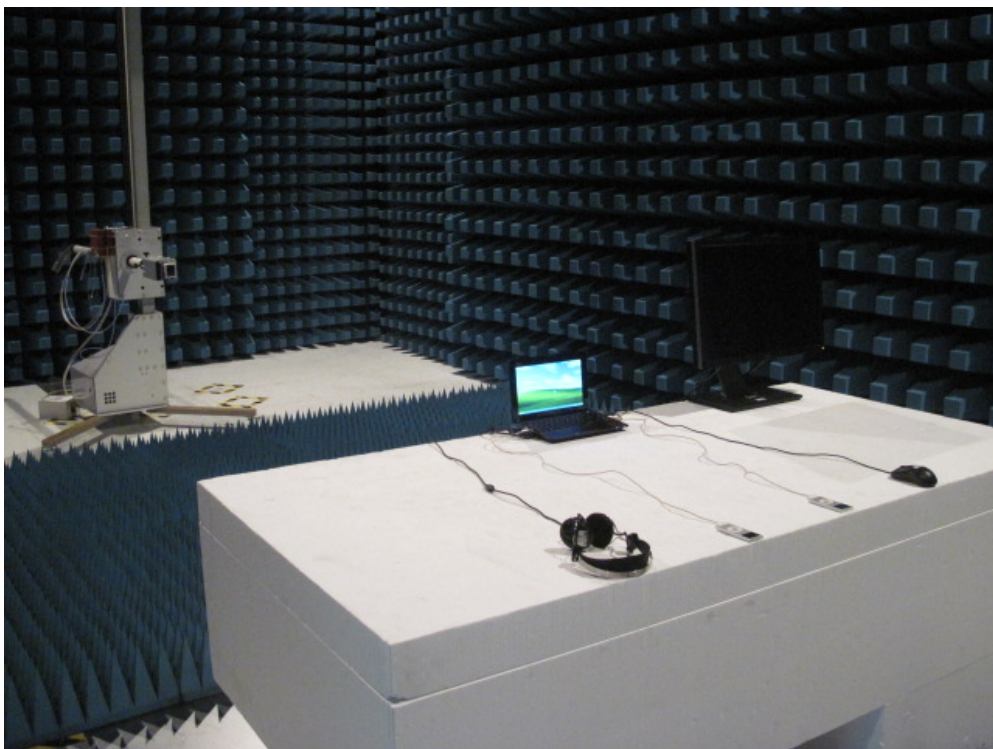
Test Mode : Transmitting

Description : Back View of Radiated Emission Test Setup for 1~18GHz



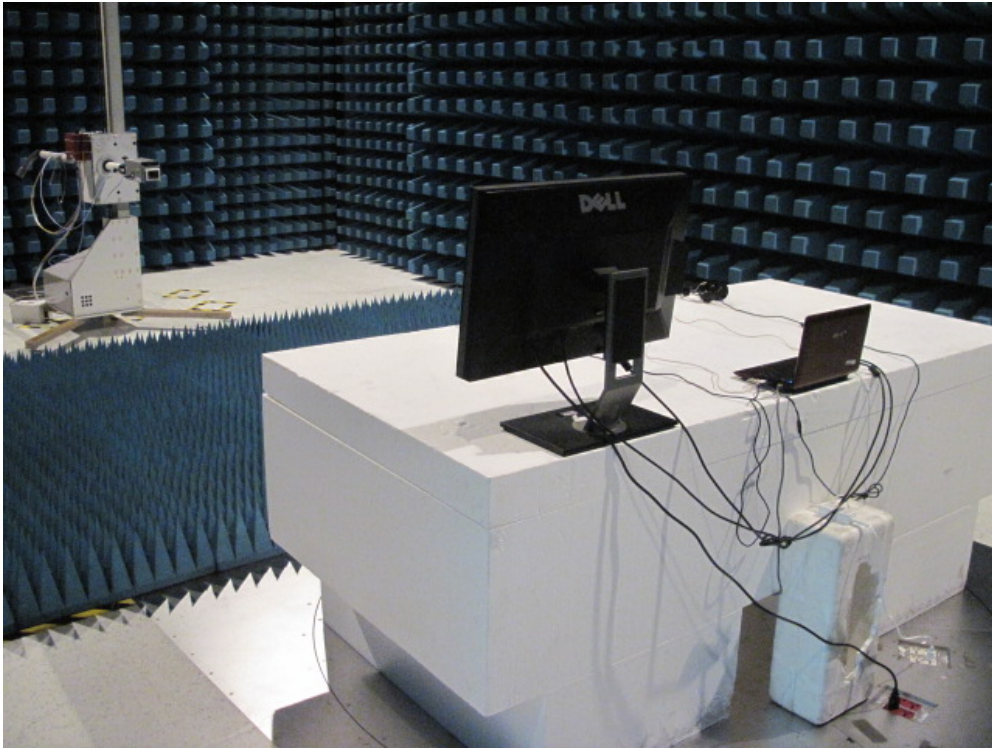
Test Mode : Transmitting

Description : Front View of Radiated Emission Test Setup for Above 18GHz



Test Mode : Transmitting

Description : Back View of Radiated Emission Test Setup for Above 18GHz



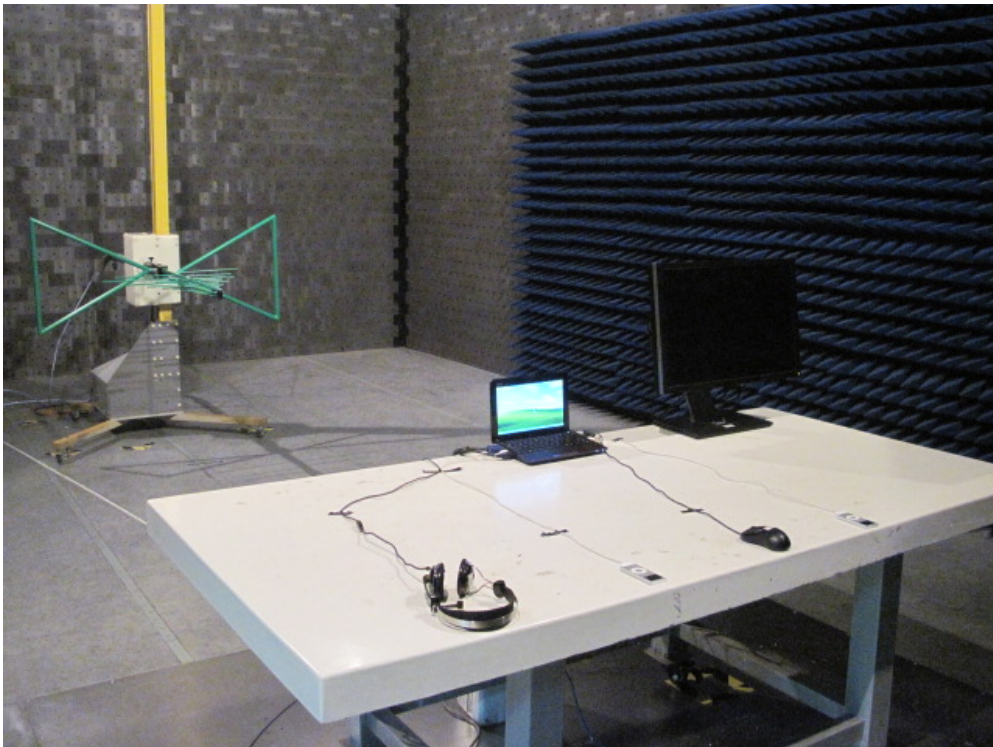
Description: Front View of Conducted Emission Test Setup



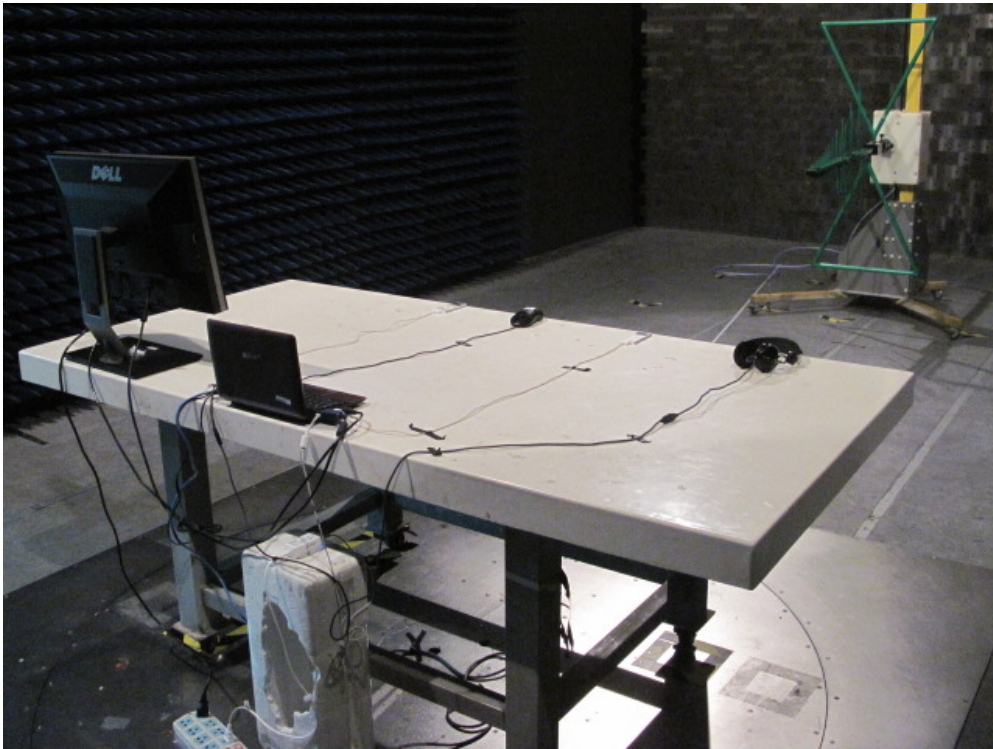
Description: Front View of Conducted Emission Test Setup



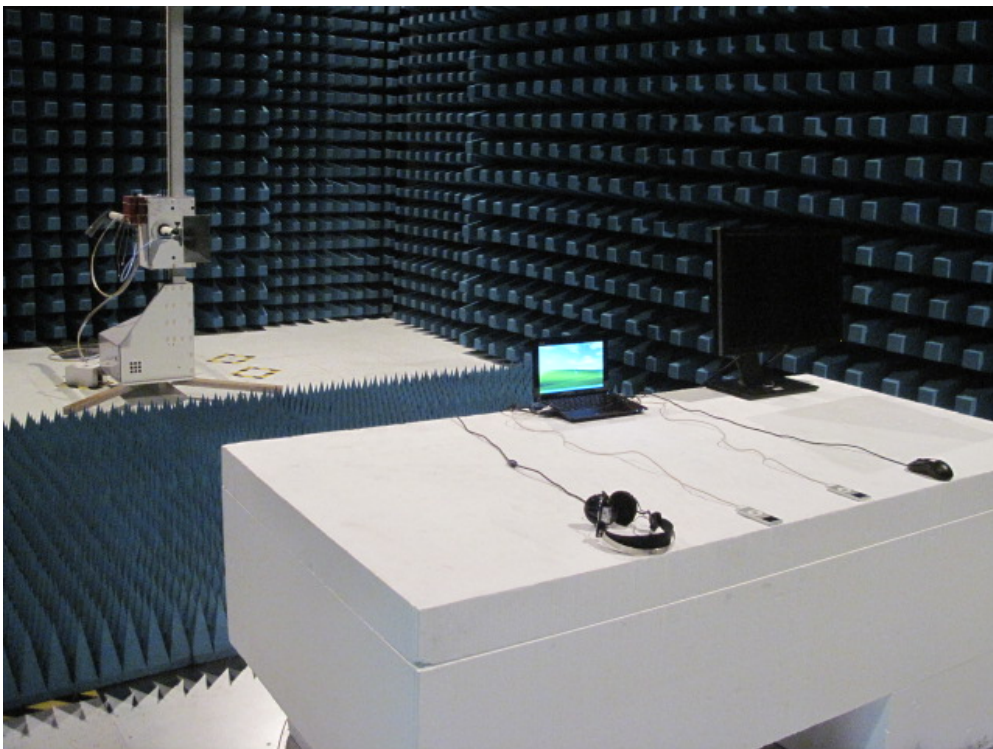
Description: Front View of Radiated Emission Test Setup for Below 1GHz



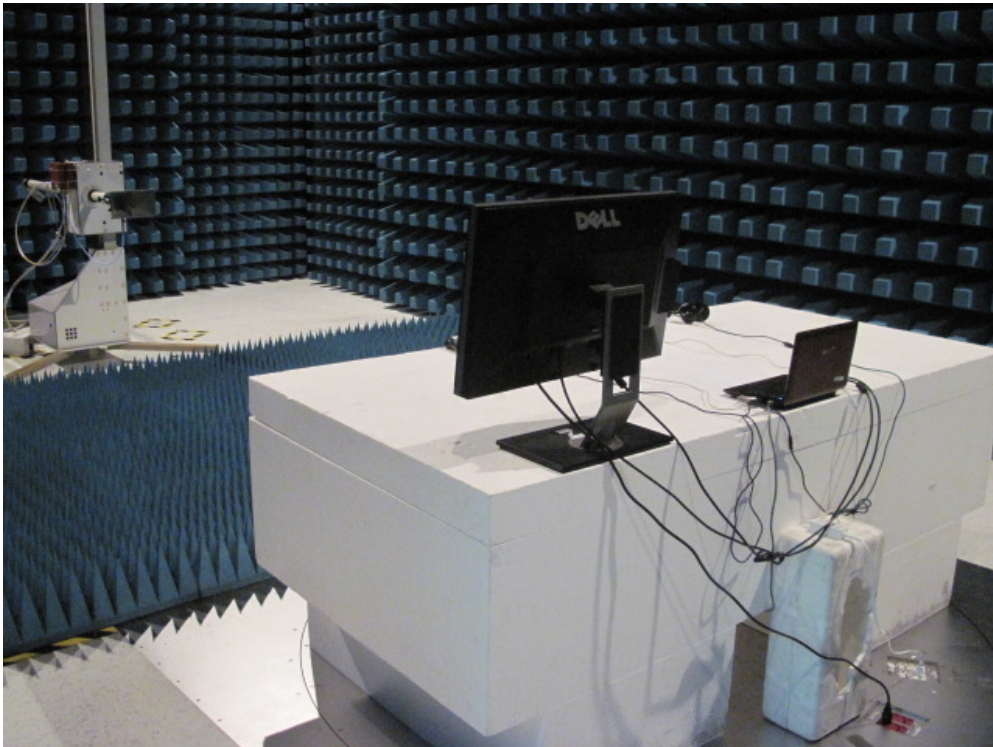
Description: Back View of Radiated Emission Test Setup for Below 1GHz



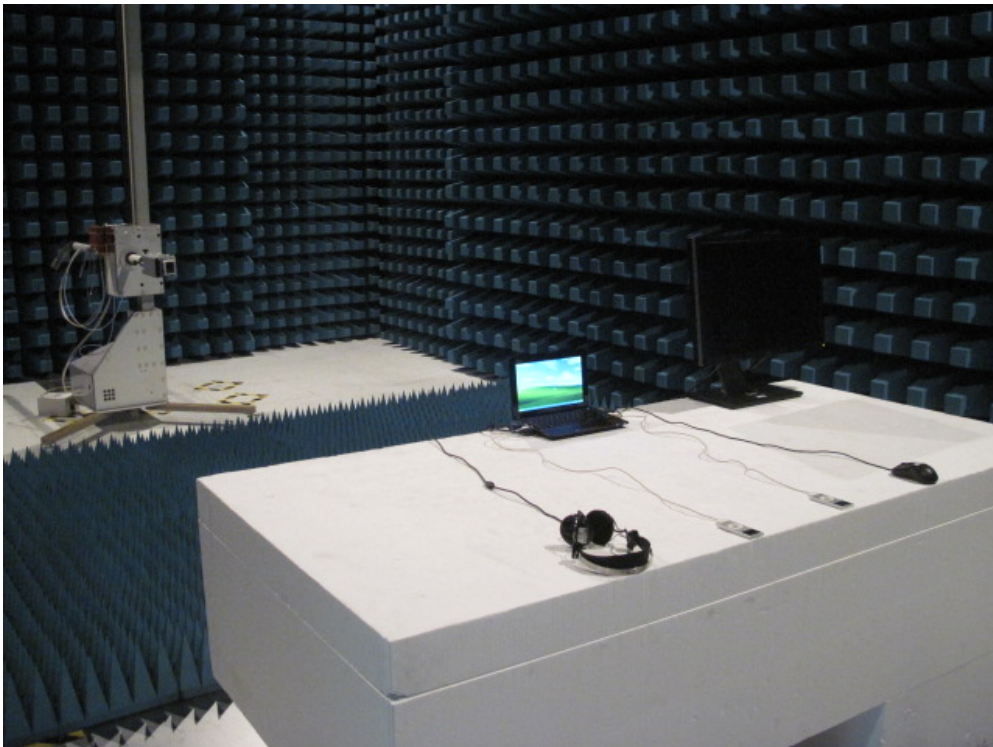
Description: Front View of Radiated Emission Test Setup for Above 1GHz



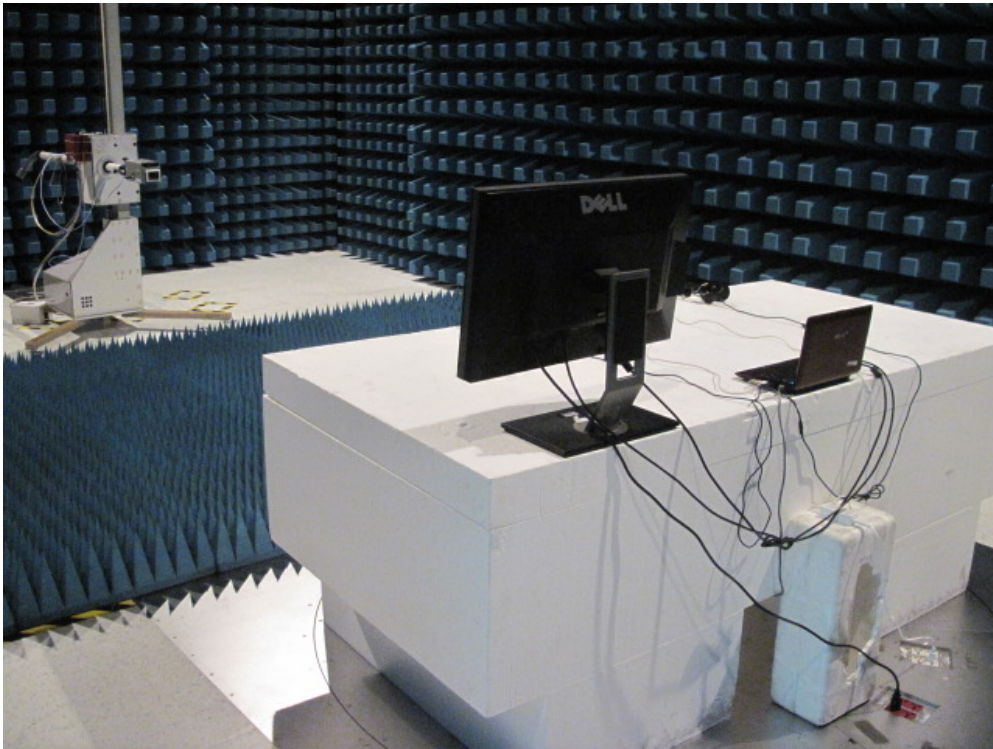
Description: Back View of Radiated Emission Test Setup for Above 1GHz



Description: Front View of Radiated Emission Test Setup for Above 18GHz



Description: Back View of Radiated Emission Test Setup for Above 1GHz



SAR Test Setup



Depth of the liquid in the phantom – Zoom in

Note: The position used in the measurements were according to IEEE 1528 - 2003

